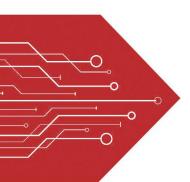
## MSKSEMI















**ESD** 

TVS

TSS

MOV

GDT

**PLED** 

# Broduct data sheet



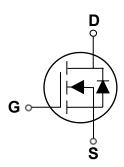








SOT-23-3L



#### Features

- 20 V, 6A, RDS(ON)=18mΩ@VGS=4.5V
- Improved dv/dt capability
- Fast switching
- Green Device Available

#### **Applications**

- Notebook
- Load Switch
- Hend-Held Instruments

BVDSS	RDSON	ID
20V	18mΩ	6A

#### Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	20	V
V <sub>G</sub> S	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T <sub>C</sub> =250)	6.0	А
lD	Drain Current – Continuous (T <sub>C</sub> =1000)	4.0	А
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	24	А
Б	Power Dissipation (T <sub>C</sub> =250)	1.56	W
P <sub>D</sub>	Power Dissipation – Derate above 250	0.012	W/ C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	С
TJ	Operating Junction Temperature Range	-55 to 150	С

#### Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reia	Thermal Resistance Junction to ambient		80	C/ W



#### Off Characteristics

Symbol	Parameter	Conditions		Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	n-Source Breakdown Voltage V <sub>GS</sub> =0V , I <sub>D</sub> =250uA			1	V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 250 , I <sub>D</sub> =1mA		0.02		V/ C
	Drain-Source Leakage Current	V <sub>DS</sub> =20V , V <sub>GS</sub> =0V , T <sub>J</sub> =250			1	uA
IDSS		V <sub>DS</sub> =16V , V <sub>GS</sub> =0V , T <sub>J</sub> =1250			10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±12V , V <sub>DS</sub> =0V			±100	nA

#### On Characteristics

Rds(on)	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		18	26	mΩ	
		V <sub>GS</sub> =2.5V , I <sub>D</sub> =4A		24	40	1115.2	
V <sub>GS(th)</sub>	Gate Threshold Voltage	\/=\/	0.4	0.7	1.1	٧	
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	-V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA		2		mV/ C	
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>S</sub> =4A		9.5		8	

#### Dynamic and switching Characteristics

Qg	Total Gate Charge <sup>2,3</sup>			5.8		
Qgs	Gate-Source Charge <sup>2,3</sup>	$V_{DS}$ =10V , $V_{GS}$ =4.5V , $I_{D}$ =4A		0.6	1	nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>			2		
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>			5.0	1	
Tr	Rise Time <sup>2, 3</sup>	$V_{DD}$ =10V , $V_{GS}$ =4.5V , $R_{G}$ =25 $\Omega$		14.4		nS
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2,3</sup>	I <sub>D</sub> =1A		30.0		113
T <sub>f</sub>	Fall Time <sup>2,3</sup>			9.2		
Ciss	Input Capacitance			600		
Coss	Output Capacitance	V <sub>DS</sub> =10V , V <sub>GS</sub> =0V , F=1MHz		70	1	pF
Crss	Reverse Transfer Capacitance			45		

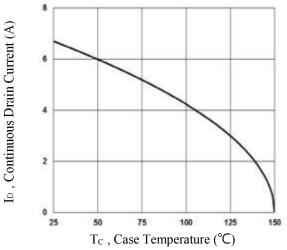
#### Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions		Тур.	Max.	Unit
Is	Continuous Source Current	\\ -\\ -0\\			6.0	Α
lsм	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			12	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =250			1.2	V

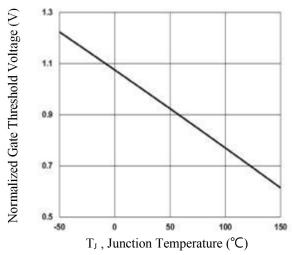
#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width  $\leq$  300 us , duty cycle  $\leq$  2%.
- Essentially independent of operating temperature.

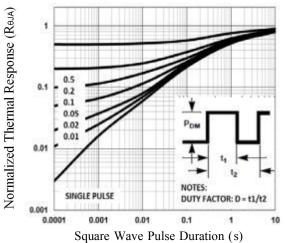




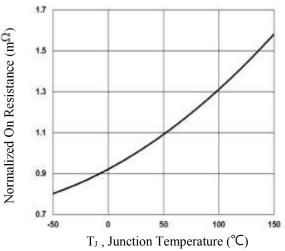
Continuous Drain Current vs. T<sub>c</sub> Fig. 1



Normalized  $V_{\text{th}}$  vs.  $\ T_{\text{J}}$ Fig. 3



Normalized Transient Impedance Fig. 5



Normalized RDSON vs. T<sub>J</sub> Fig. 2

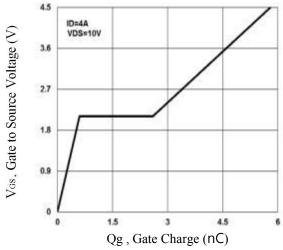


Fig. 4 Gate Charge Waveform

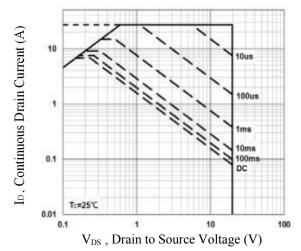
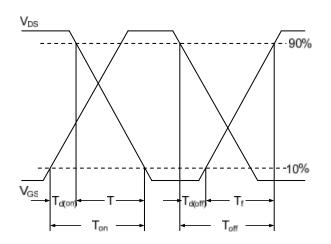


Fig. 6 Maximum Safe Operation Area





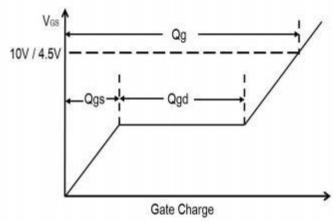


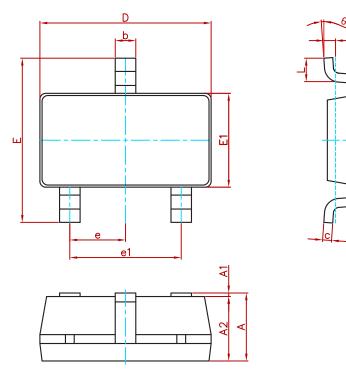
Fig. 7 Switching Time Waveform

Fig. 8 Gate Charge Waveform



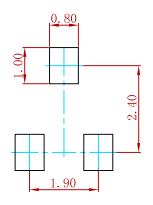
0.200

#### **PACKAGE MECHANICAL DATA**



Symbol	Dimensions In Millimeters		Dimensions In Inche		
Symbol	Min.	Max.	Min.	Max.	
Α	1.050	1.250	0.041	0.049	
A1	0.000	0.100	0.000	0.004	
A2	1.050	1.150	0.041	0.045	
b	0.300	0.500	0.012	0.020	
С	0.100	0.200	0.004	0.008	
D	2.820	3.020	0.111	0.119	
E1	1.500	1.700	0.059	0.067	
E	2.650	2.950	0.104	0.116	
е	0.950(	BSC)	0.037(	(BSC)	
e1	1.800	2.000	0.071	0.079	
L	0.300	0.600	0.012	0.024	
θ	0°	8°	0°	8°	

### **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
AO3420	SOT-23-3L	3000



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